

Notice of References Cited

Application/Control No.

10/597,976

Applicant(s)/Patent Under
Reexamination
REDERT ET AL.

Examiner

Carlos Perromat

Art Unit

2628

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	V	Z. Wu, L. Li; A Line-Integration Based Method for Depth Recovery from Surface Normals; IEEE, November 1988
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.